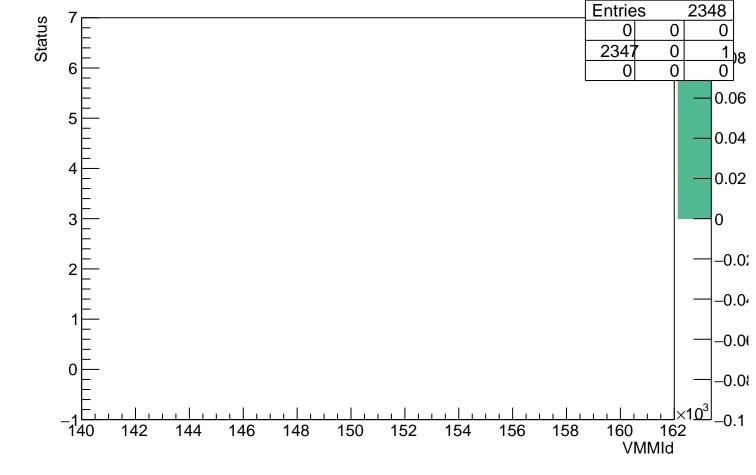
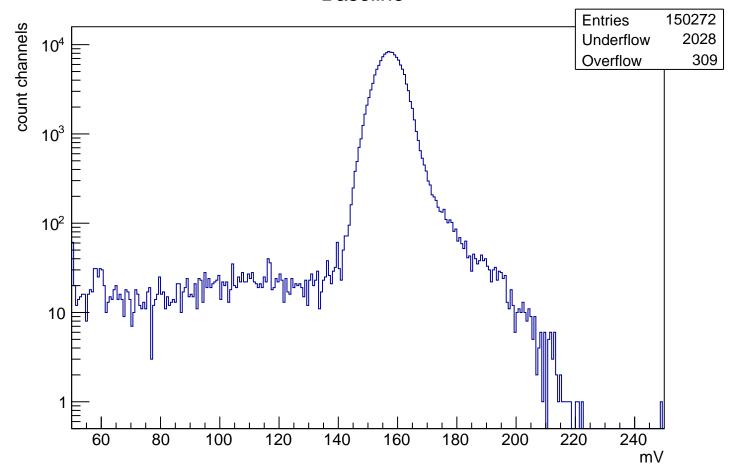
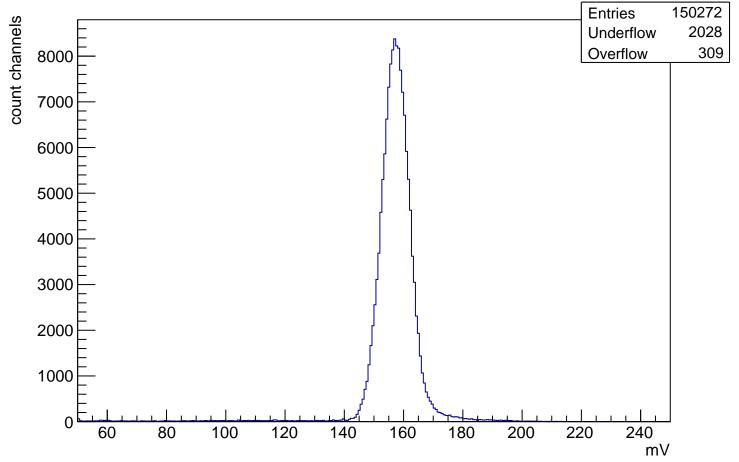
Status VS VMMID



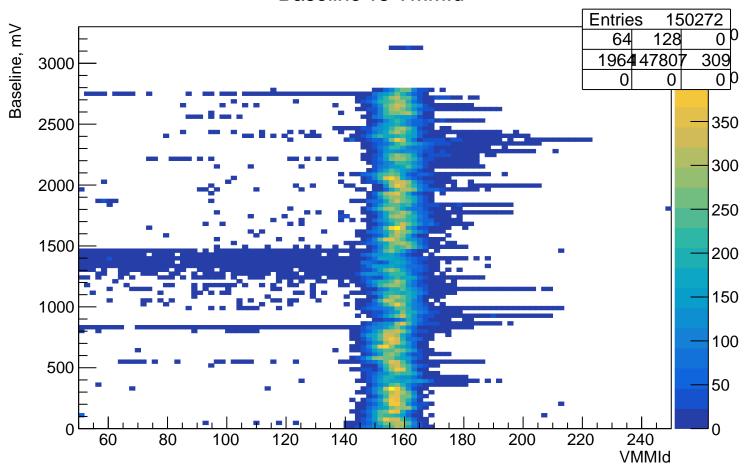
Baseline



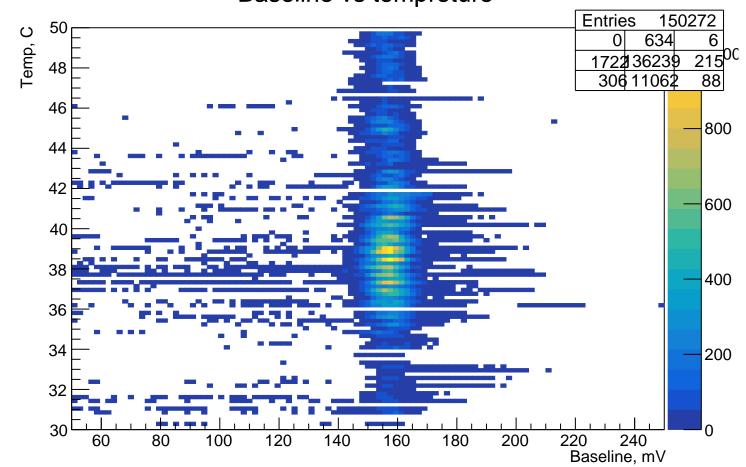
Baseline



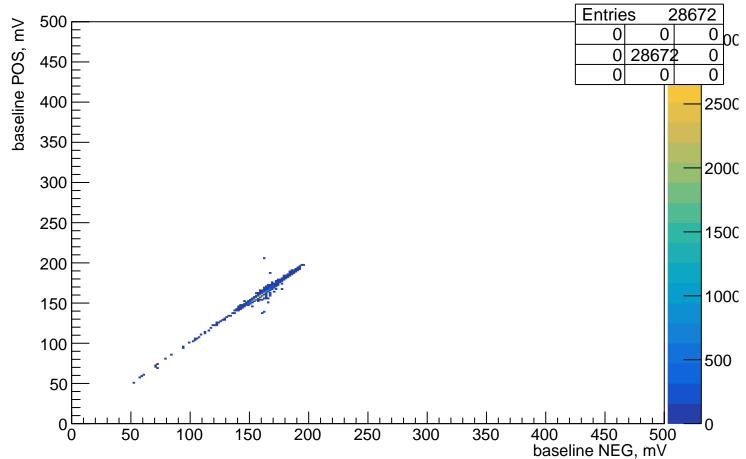
Baseline vs VMMId



Baseline vs tempreture



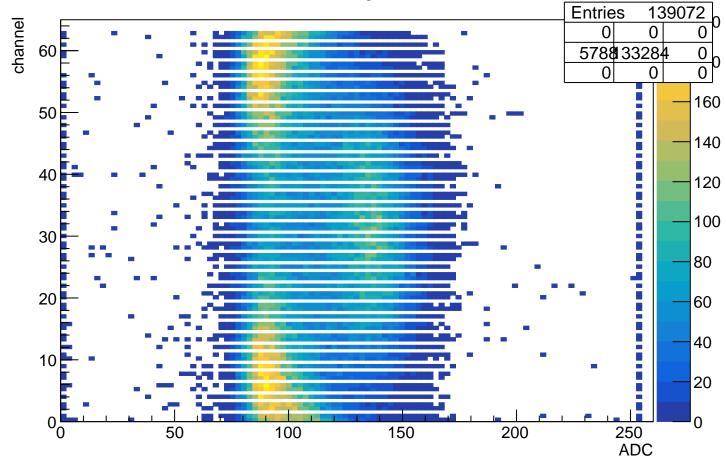
Bline pos (delay 2 ms) vs Bline neg (delay 0 ms) - not failed



PDO mean L0 negative (all VMM) Entries channel ADC

PDO entries mean L0 negative Entries channel 0 00 1400 100C **Entries**

TDO mean L0 negative (all VMM)

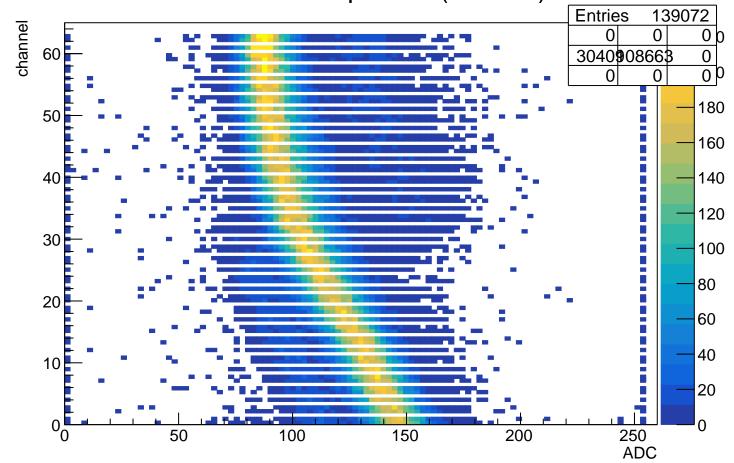


TDO entries mean L0 negative Entries channel 0 00 1400 100C **Entries**

PDO mean L0 positive (all VMM) Entries channel ADC

PDO entries mean L0 positive Entries channel 0 0 0 0 0 100C **Entries**

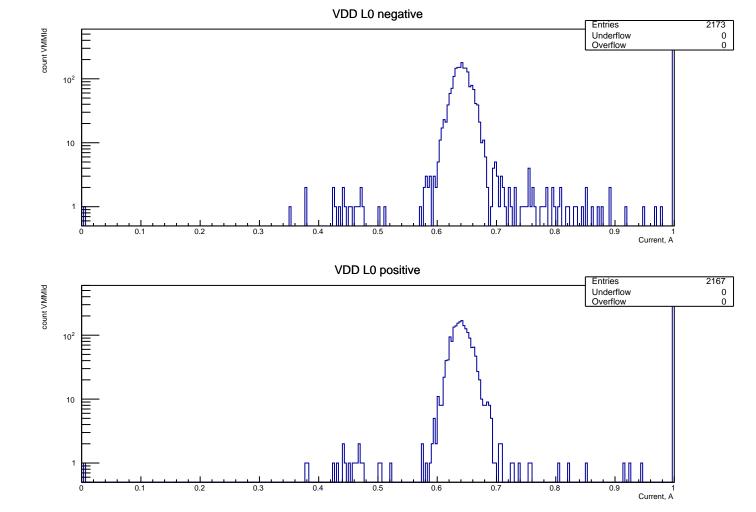
TDO mean L0 positive (all VMM)

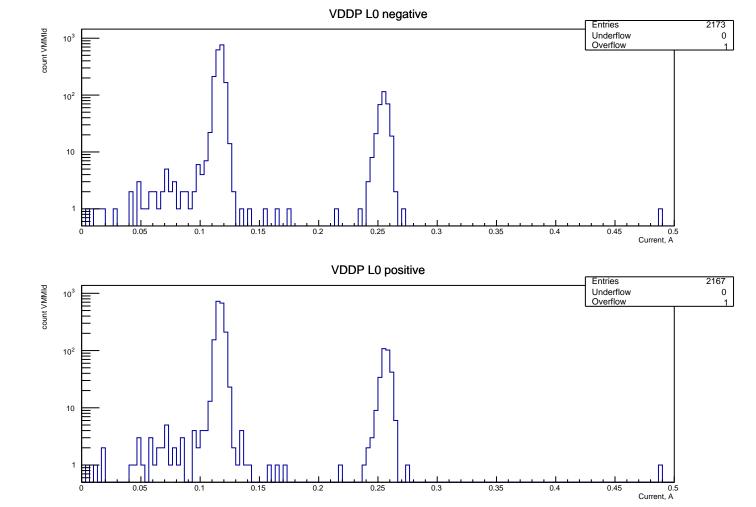


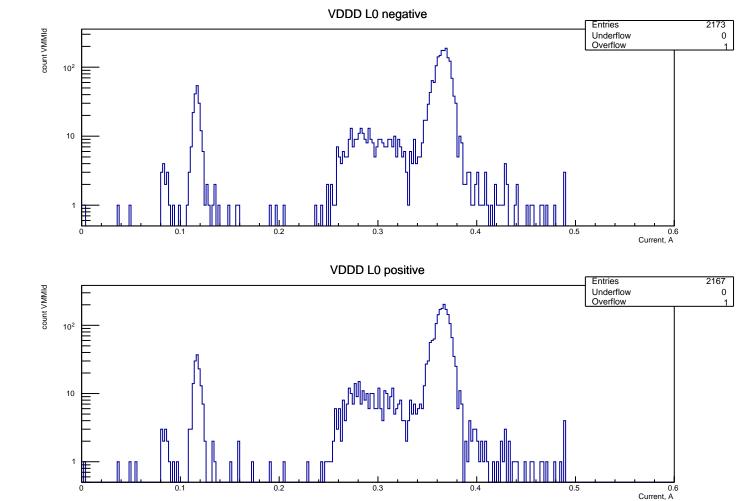
TDO entries mean L0 positive Entries channel 0 0 0 0 0 100C **Entries**

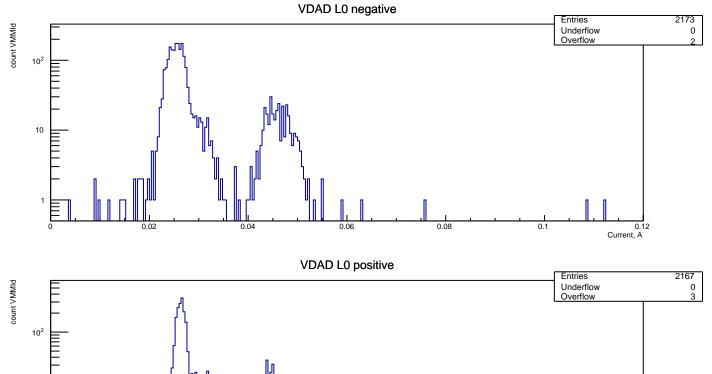
DDO mean negative (all VMM) Entries channel 580\$13311\$ ADC

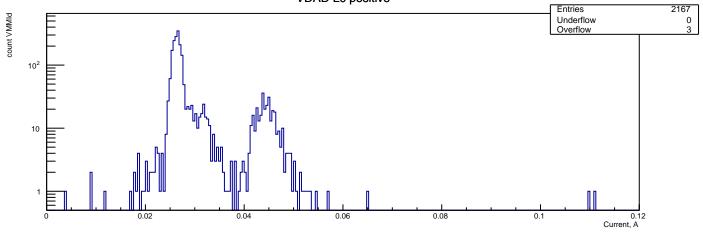
DDO mean positive (all VMM) Entries channel ADC

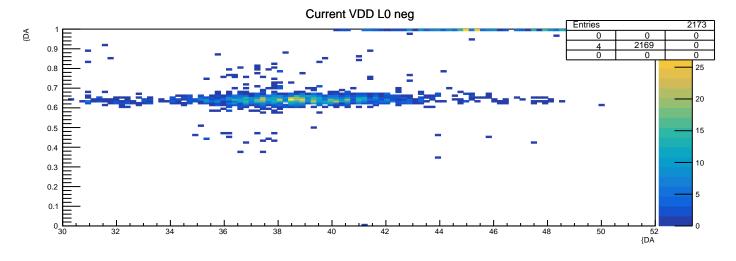


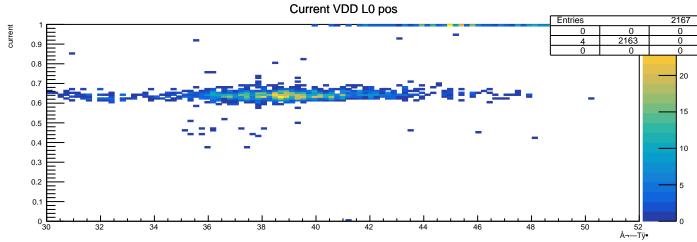


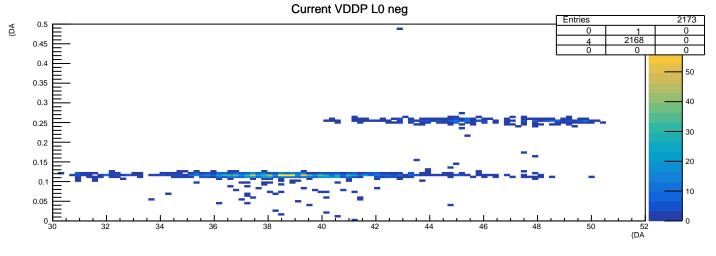


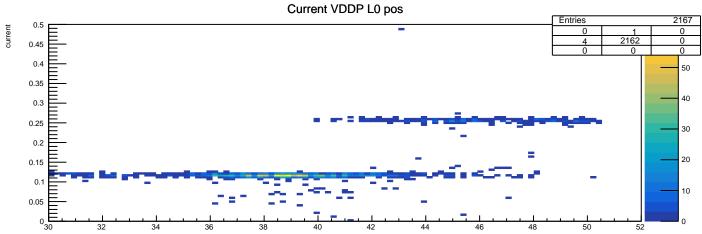


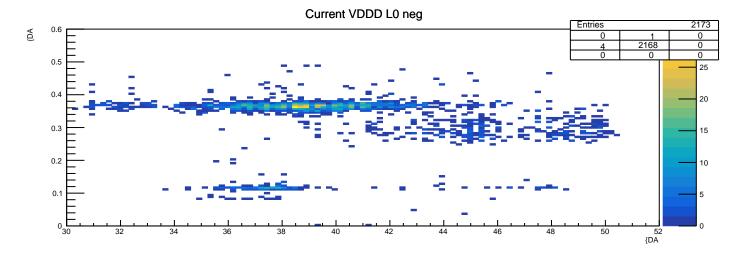


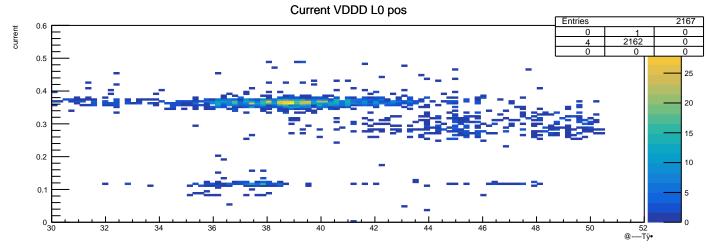


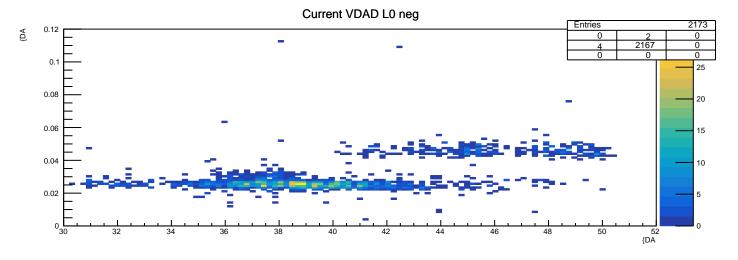


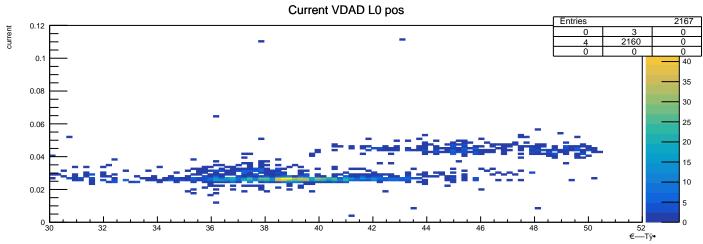


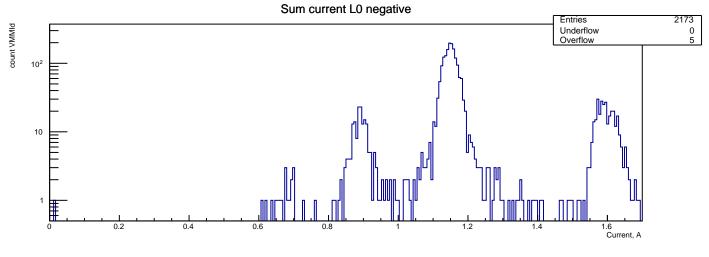


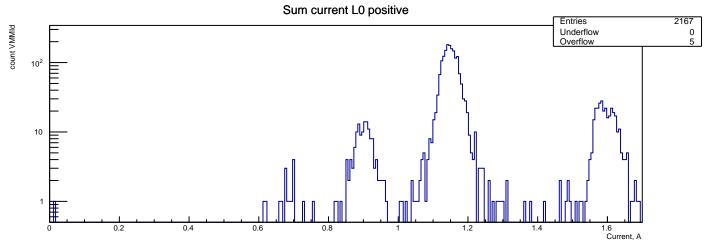




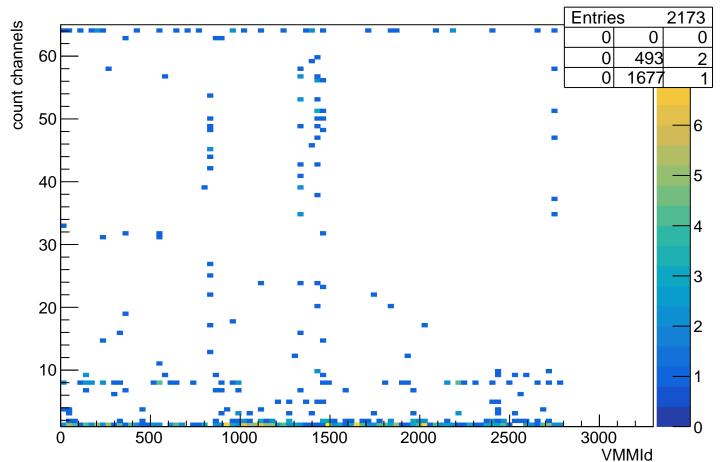




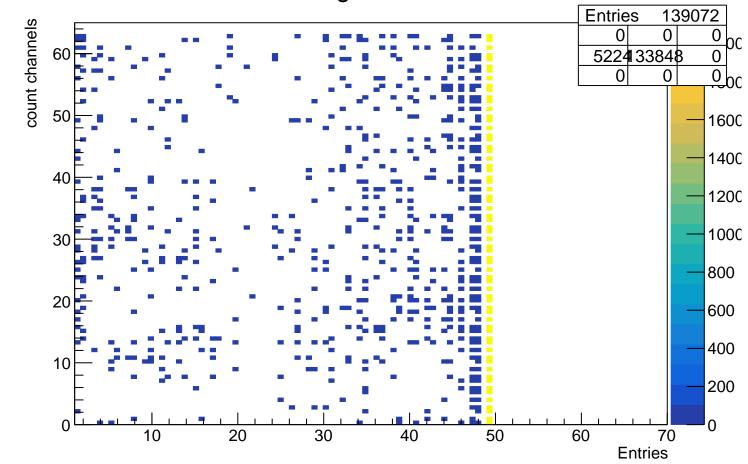




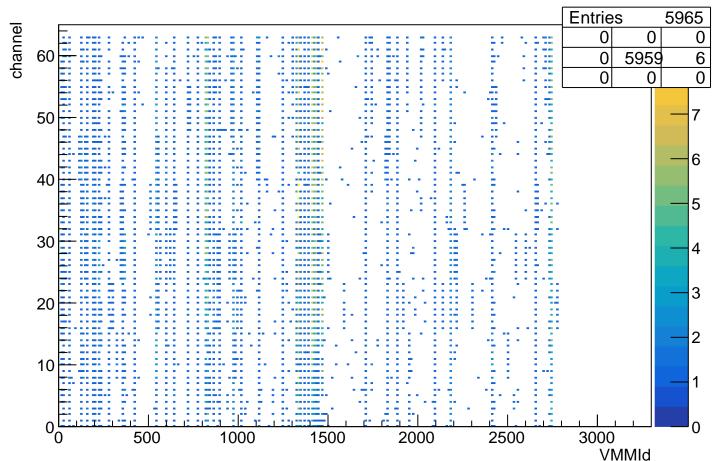
Number of channels with bad ART negative (zero means no defects channels in chip)



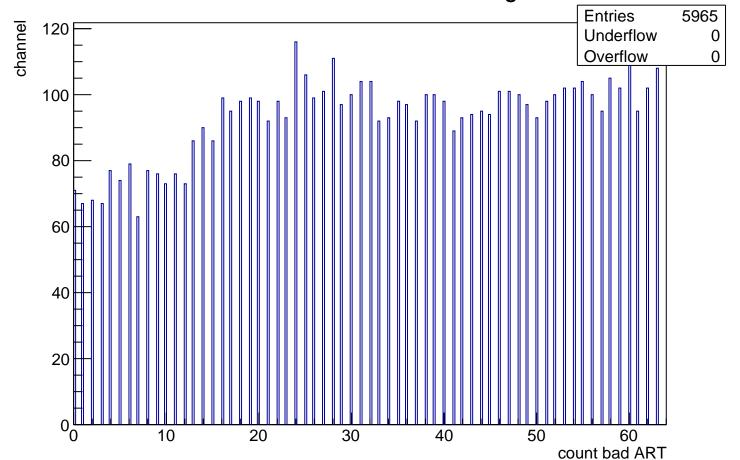
ART negative entries



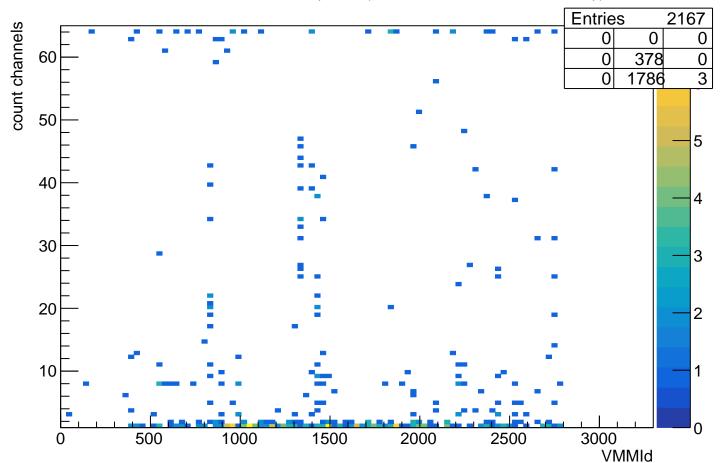
VMMId with bad ART negative (zero means no defects channels in chip)



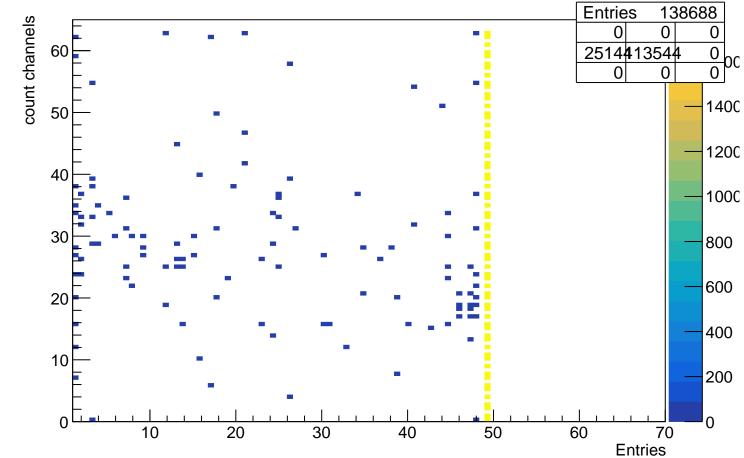
count Bad channel in ART negative



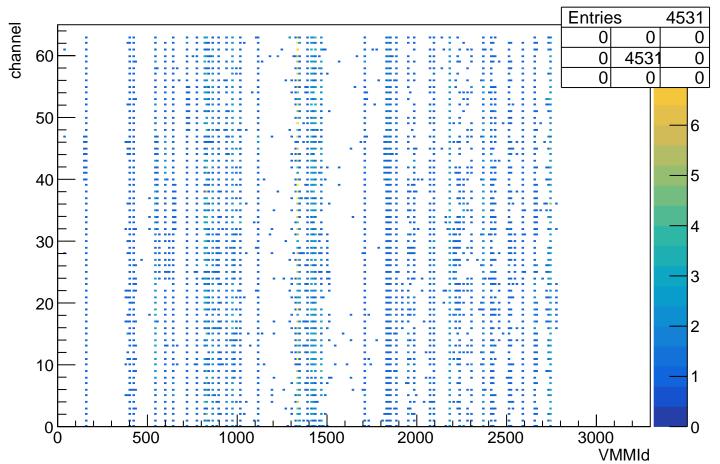
Number of channels with bad ART positive (zero means no defects channels in chip)



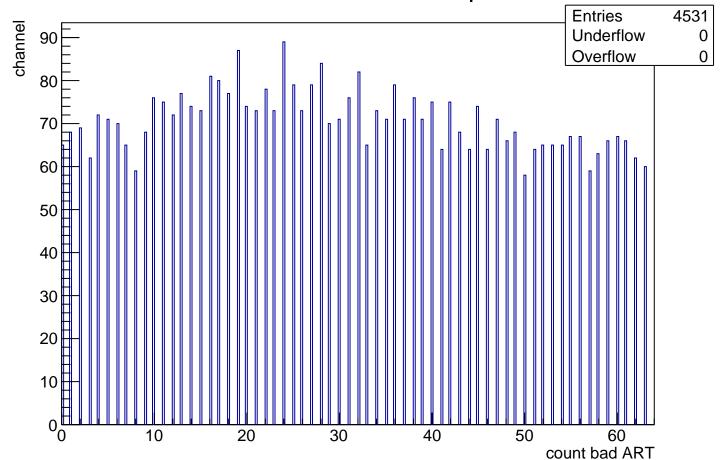
ART positive entries

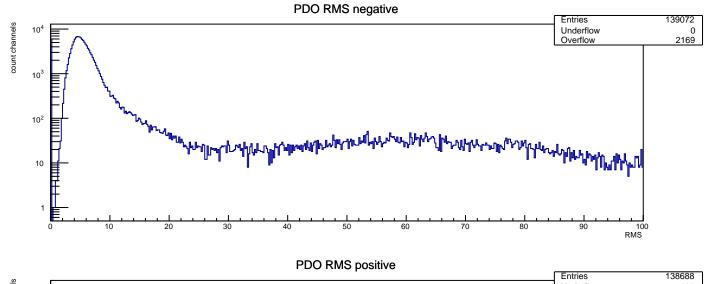


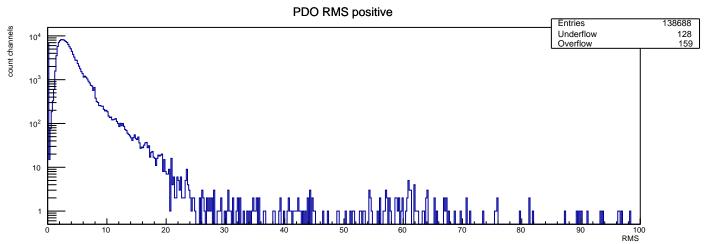
VMMId with bad ART positive (zero means no defects channels in chip)



count Bad channel in ART positive







Baseline RMS Entries 150272 count channels 128 Underflow 10^{4} Overflow 1398 10³ 10² 10 0.2 0.4 0.6 8.0 1.2 1.4 1.6 1.8 2 RMS

